## 1. **DESCRIPTION**

The XL5615 and XD5615 are 10-bit voltage output digital-to-analog converter (DAC) with a buffered reference input (high impedance). The DAC has an output voltage range that is two times the reference voltage, and the DAC is monotonic. The device is simple to use, running from a single supply of 5V. A power-on-reset function is incorporated to ensure repeatable start-up conditions.

Digital control of the XL5615 and XD5615 are over a three-wire serial bus that is CMOS compatible and easily interfaced to industry standard microprocessor and microcontroller devices. The device receives a 16-bit data word to produce the analog output. The digital inputs feature Schmitt triggers for high noise immunity. Digital communication protocols include the SPI<sup>™</sup>, QSPI<sup>™</sup>, and Microwire<sup>™</sup> standards.

The 8-terminal small-outline D package allows digital control of analog functions in space-critical applications. The XL5615 and XD5615 are characterized for operation from -40°C to +85°C.

### 2. FEATURES

- 10-Bit CMOS Voltage Output DAC in an 8-Terminal Package
- 5V Single Supply Operation
- 3-Wire Serial Interface
- High-Impedance Reference Inputs
- Voltage Output Range: 2 Times the Reference Input Voltage
- Internal Power-On Reset
- Low Power Consumption: 1.75mW Max
- Update Rate of 1.21MHz
- Settling Time to 0.5LSB: 12.5µs Typ
- Monotonic Over Temperature

### 3. TYPICAL APPLICATION

- Battery-Powered Test Instruments
- Digital Offset and Gain Adjustment
- Battery Operated/Remote Industrial Controls
- Machine and Motion Control Devices
- Cellular Telephones



### 4. PIN CONFIGURATIONS AND FUNCTIONS



| TERMINAL        |     | 1/0 |                                       |  |  |
|-----------------|-----|-----|---------------------------------------|--|--|
| NAME            | NO. | 1/0 | DESCRIPTION                           |  |  |
| DIN             | 1   | I   | Serial data input                     |  |  |
| SCLK            | 2   | I   | Serial clock input                    |  |  |
| CS              | 3   | I   | Chip select, active low               |  |  |
| DOUT            | 4   | 0   | Serial data output for daisy chaining |  |  |
| AGND            | 5   |     | Analog ground                         |  |  |
| REFIN           | 6   | I   | Reference input                       |  |  |
| OUT             | 7   | 0   | DAC analog voltage output             |  |  |
| V <sub>DD</sub> | 8   |     | Positive power supply                 |  |  |

## 5. BLOCK DIAGRAM





## 6. ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

|  | UNIT                |                  |  |
|--|---------------------|------------------|--|
| Supply voltage (V <sub>DD</sub> to AGND)             | 7V                  |                  |  |
| Digital input voltage range to AGND                  | -0.3V to VDD + 0.3V |                  |  |
| Reference input voltage range to AGND                | -0.3V to VDD + 0.3V |                  |  |
| Output voltage at OUT from external source           | VDD + 0.3V          |                  |  |
| Continuous current at any terminal                   |                     | 20mA             |  |
| Operating free-air temperature range, T <sub>A</sub> | XL5615              | -40 °C to +85 °C |  |
| XD5615   |                     | -40°C to +85°C   |  |
| Storage temperature range, T <sub>stg</sub>          | -65°C to +150°C     |                  |  |
| Lead temperature 1,6mm (1/16 inch) from case         | for 10 seconds      | +260°C           |  |

Stressesbeyondthosel i stedunderAbsol uteMaxi mumRati ngsmaycausepermanentdamagetothedevi ce. Thesearestress rati ngsonly, andfuncti onal operati onofthedevi ceattheseoranyothercondi ti onsbeyondthosei ndi catedunder RecommendedOperati ngCondi ti onsi snoti mplied. Exposuretoabsol ute-maxi mum-ratedcondi ti onsforextendedperi ods may affectdevi cerel i abili ty.

## 7. RECOMMENDED OPERATING CONDITIONS

|   |        | MIN | NOM   | MAX                | UNIT |
|---|--------|-----|-------|--------------------|------|
| Supply voltage, V <sub>DD</sub>                       |        | 4.5 | 5     | 5.5                | V    |
| High-level digital input voltage, V <sub>IH</sub>     |        | 2.4 |       |                    | V    |
| Low-level digital input voltage, V <sub>IL</sub>      |        |     |       | 0.8                | V    |
| Reference voltage, V <sub>ref</sub> to REFIN terminal |        | 2   | 2.048 | V <sub>DD</sub> -2 | V    |
| Load resistance, R <sub>L</sub>                       |        | 2   |       |                    | kΩ   |
|   | XL5615 | -40 |       | 85                 | °C   |
| Operating free-air temperature, I <sub>A</sub>        | XD5615 | -40 |       | 85                 | °C   |

### 8. ELECTRICAL CHARAC TERISTICS

over recommended operating free-air temperature range, V\_{DD} = 5V  $\pm$  5%, V\_{ref} = 2.048V (unless otherwise noted)

| STATI                           | C DAC SPECIFICATIONS           |   |   |     |                         |        |      |
|---------------------------------|--------------------------------|---|---|-----|-------------------------|--------|------|
|                                 | PARAMETER                      |   | TEST CONDITIONS                         | MIN | ТҮР                     | MAX    | UNIT |
|                                 | Resolution                     |   |   | 10  |                         |        | bits |
|                                 | Integral nonlinearity, end po  | oint adjusted (INL)                           | $V_{ref} = 2.048V$ , See <sup>(1)</sup> |     |                         | ±1     | LSB  |
| Differential nonlinearity (DNL) |                                |   | $V_{ref} = 2.048V$ , See <sup>(2)</sup> |     | ±0.1                    | ±0.5   | LSB  |
| E <sub>ZS</sub>                 | Zero-scale error (offset error | V <sub>ref</sub> = 2.048V, See <sup>(3)</sup> |   |     | ±3                      | LSB    |      |
|                                 | Zero-scale-error temperatur    | V <sub>ref</sub> = 2.048V, See <sup>(4)</sup> |   | 3   |                         | ppm/°C |      |
| E <sub>G</sub>                  | Gain error                     |   | $V_{ref} = 2.048V$ , See <sup>(5)</sup> |     |                         | ±3     | LSB  |
|                                 | Gain-error temperature coe     | V <sub>ref</sub> = 2.048V, See <sup>(6)</sup> |   | 1   |                         | ppm/°C |      |
| DCDD                            | Device events estention estin  | Zero scale                                    | Sec (7)(8)                              | 80  |                         |        | dD   |
| PSRK                            | Power-supply rejection ratio   | Gain  | See (1)(-)                              | 80  |                         |        | aв   |
| Analog full scale output        |                                |   | $R_L = 100k\Omega$                      |     | 2V <sub>ref</sub> (1023 | /1024) | V    |

(1) The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors (see text). Tested from code 3 to code 1024.

- (2) The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code. Tested from code 3 to code 1024.
- (3) Zero-scale error is the deviation from zero-voltage output when the digital input code is zero (see text).
- (4) Zero-scale-error temperature coefficient is given by:EZS TC = [EZS (Tmax) EZS (Tmin)]/Vref  $\times$  106/(Tmax–Tmin).
- (5) Gain error is the deviation from the ideal output (Vref 1LSB) with an output load of 10kΩ excluding the effects of the zeroscale error.
- (6) Gain temperature coefficient is given by:  $E_G TC = [E_G(T_{max}) E_G (T_{min})]/V_{ref} \times 10^6/(T_{max} T_{min})$ .
- (7) Zero-scale-error rejection ratio (EZS-RR) is measured by varying the VDD from 4.5V to 5.5V dc and measuring the proportion of this signal imposed on the zero-code output voltage.
- (8) Gain-error rejection ratio (EG-RR) is measured by varying the VDD from 4.5V to 5.5V dc and measuring the proportion of this signal imposed on the full-scale output voltage after subtracting the zero-scale change.



# 9. VOLTAGE OUTPUT(OUT)

| PA                    | RAMETER                                  | TEST CONDIT  | IONS                      | MIN                | ТҮР    | MAX                  | UNIT |
|-----------------------|--|--|---------------------------|--------------------|--------|----------------------|------|
| Vo                    | Voltage output range                     | $R_L=10k\Omega$  |                           | 0                  |        | V <sub>DD</sub> -0.4 | V    |
|                       | Output load regulation<br>accuracy       | V <sub>O(OUT)</sub> = 2V,  | $R_L = 2k\Omega$          |                    |        | 0.5                  | LSB  |
| I <sub>OSC</sub>      | Output short circuit current             | OUT to $V_{DD}$ or AGND  |                           |                    | 2<br>0 |                      | mA   |
| V <sub>OL(low)</sub>  | Output voltage, low-level                | I <sub>O(OUT)</sub> ≤ 5mA  |                           |                    |        | 0.25                 | V    |
| V <sub>OH(high)</sub> | Output voltage, high-level               | I <sub>O(OUT)</sub> ≤− 5mA   |                           | 4.75               |        |                      | V    |
| REFEREN               | ICE INPUT (REFIN)                        |  |                           |                    |        |                      |      |
| VI                    | Input voltage                            |  |                           | 0                  |        | V <sub>DD</sub> -2   | V    |
| r <sub>i</sub>        | Input resistance                         |  |                           | 10                 |        |                      | MΩ   |
| Ci                    | Input capacitance                        |  |                           |                    | 5      |                      | pF   |
| DIGITAL               | INPUTS (DIN, SCLK, CS)                   |  |                           |                    |        |                      |      |
| V <sub>IH</sub>       | High-level digital input voltage         |  |                           | 2.4                |        |                      | V    |
| V <sub>IL</sub>       | Low-level digital input voltage          |  |                           |                    |        | 0.8                  | V    |
| I <sub>IH</sub>       | High-level digital input current         | V <sub>I</sub> = V <sub>DD</sub>   |                           |                    |        | ±1                   | μΑ   |
| I <sub>IL</sub>       | Low-level digital input current          | V <sub>1</sub> = 0   |                           |                    |        | ±1                   | μΑ   |
| Ci                    | Input capacitance                        |  |                           |                    | 8      |                      | pF   |
| DIGITAL               | OUTPUT (DOUT)                            |  |                           |                    |        |                      |      |
| V <sub>OH</sub>       | Output voltage, high-level               | I <sub>0</sub> = -2mA  |                           | V <sub>DD</sub> -1 |        |                      | V    |
| V <sub>OL</sub>       | Output voltage, low-level                | I <sub>0</sub> = 2mA   |                           |                    |        | 0.4                  | V    |
| POWER                 | SUPPLY                                   |  |                           |                    |        |                      |      |
| V <sub>DD</sub>       | Supply voltage                           |  |                           | 4.5                | 5      | 5.5                  | V    |
| I <sub>DD</sub>       | Power supply current                     | $V_{DD}$ = 5.5V, No<br>load, All inputs =<br>OV or V <sub>DD</sub>             | V <sub>ref</sub> = 0      |                    | 150    | 250                  | μА   |
|                       |  | $V_{DD}$ = 5.5V, No<br>load, All inputs =<br>0V or V <sub>DD</sub>             | V <sub>ref</sub> = 2.048V |                    | 230    | 350                  | μΑ   |
| ANALOG                | OUTPUT DYNAMIC PERFORMANC                | E  |                           |                    |        |                      |      |
|                       | Signal-to-noise + distortion,<br>S/(N+D) | $V_{ref} = 1V_{PP}$ at 1kHz +<br>2.048Vdc, code = 11 11<br>1111 <sup>(1)</sup> | 11                        | 60                 |        |                      | dB   |

[1] The limiting frequency value at  $1V_{PP}$  is determined by the output-amplifier slew rate.

# **10. DIGITAL INPUT TIMING REQUIREMENTS (See Figure 1)**

|                      | PARAMETER  | MIN | NOM | МАХ | UNIT |
|----------------------|--|-----|-----|-----|------|
| t <sub>su(DS)</sub>  | Setup time, DIN before SCLK high                     | 45  |     |     | ns   |
| t <sub>h(DH)</sub>   | Hold time, DIN valid after SCLK high                 | 0   |     |     | ns   |
| t <sub>su(CSS)</sub> | Setup time, CS low to SCLK high                      | 1   |     |     | ns   |
| t <sub>su(CS1)</sub> | Setup time, CS high to SCLK high                     | 50  |     |     | ns   |
| t <sub>h(CSH0)</sub> | Hold time, SCLK low to CS low                        | 1   |     |     | ns   |
| t <sub>h(CSH1)</sub> | Hold time, SCLK low to CS high                       | 0   |     |     | ns   |
| t <sub>w(CS)</sub>   | Pulse duration, minimum chip select pulse width high | 20  |     |     | ns   |
| t <sub>w(CL)</sub>   | Pulse duration, SCLK low                             | 25  |     |     | ns   |
| t <sub>w(CH)</sub>   | Pulse duration, SCLK high                            | 25  |     |     | ns   |

# **11. OUTPUT SWITCHING CHARACTERISTICS**

|                       | PARAMETER                    | TEST CONDITIONS       | MIN NOM MAX | UNIT |
|-----------------------|------------------------------|-----------------------|-------------|------|
| t <sub>pd(DOUT)</sub> | Propagation delay time, DOUT | C <sub>L</sub> = 50pF | 50          | ns   |



## **12. OPERATING CHARACTERISTICS**

over recommended operating free-air temperature range, VDD = 5V  $\pm$ 5%, Vref = 2.048V (unless otherwise noted)

|      | PARAMETER                       | MIN   | ТҮР                 | MAX | UNIT |  |      |
|------|---------------------------------|---|---------------------|-----|------|--|------|
| ANA  | LOG OUTPUT DYNAMIC PER          |   |                     |     |      |  |      |
| SR   | Output slew rate                | C <sub>L</sub> = 100pF,<br>T <sub>A</sub> = +25°C                 | $R_L = 10k\Omega$ , | 0.3 | 0.5  |  | V/µs |
| ts   | Output settling time            | Output settling time To 0.5LSB,<br>$R_L = 10k\Omega$ , $C_L = 10$ |                     |     | 12.5 |  | μs   |
|      | Glitch energy                   | DIN = All 0s to all 1s  |                     |     | 5    |  | nV-s |
| REFE | RENCE INPUT (REFIN)             |   |                     |     |      |  |      |
|      | Reference feedthrough           | REFIN = 1V <sub>PP</sub> at 1kHz + 2.048                          | Vdc <sup>(2)</sup>  |     | -80  |  | dB   |
|      | Reference<br>input<br>bandwidth |   |                     |     | 30   |  | kHz  |

[1] Settling time is the time for the output signal to remain within ±0.5LSB of the final measured value for a digital input code change of 000 hex to 3FF hex or 3FF hex to 000 hex.

[2] Reference feedthrough is measured at the DAC output with an input code = 000 hex and a  $V_{ref}$  input = 2.048Vdc +  $1V_{pp}$  at 1kHz.

#### CS th(CSH0) t<sub>su(CSS)</sub> tw(CS) th(CSH1) t<sub>su(CS1)</sub> tw(CH) tw(CL) SCLK See Note A See Note C See Note A th(DH) t<sub>su(DS)</sub> DIN tpd(DOUT) Previous LSB MSB LSB DOUT See Note B

### PARAMETER MEASUREMENT INFORMATION

NOTES: A. The input clock, applied at the SCLK terminal, should be inhibited low when  $\overline{\text{CS}}$  is high to minimize clock feedthrough. B. Data input from preceeding conversion cycle.

C. Sixteenth SCLK falling edge

### Figure 1. Timing Digram



### **TYPICAL CHARACTERISTICS**







### **TYPICAL CHARACTERISTICS (continued)**



Input Code Figure 8. Integral Nonlinearity With Input Code



### APPLICATION INFORMATION

### **GENERAL FUNCTION**

The XL5615 uses a resistor string network buffered with an op amp in a fixed gain of 2 to convert 10-bit digital data to analog voltage levels (see functional block diagram and Figure 9). The output of the XL5615 is the same polarity as the reference input (see Table 1).

An internal circuit resets the DAC register to all zeros on power up.



Figure 9. XL5615 Typical Operating Circuit

| Table 1. Dinary Code Table (ov to 2 v REFINOULPUL), Gain - 2 | Tab | ble | 1. | <b>Binary</b> | Code | Table | (0V 1 | to 2V <sub>F</sub> |  | put), | Gain : | = 2 |
|--|-----|-----|----|---------------|------|-------|-------|--------------------|--|-------|--------|-----|
|--|-----|-----|----|---------------|------|-------|-------|--------------------|--|-------|--------|-----|

| INPUT <sup>(1)</sup> |           |        | OUTPUT   |
|----------------------|-----------|--------|--|
| 1111                 | 1111      | 11(00) | 2(v <sub>REFIN</sub> ) <sup>1023</sup> /1024                 |
| 1000                 | :<br>0000 | 01(00) | :<br>2(v <sub>REFIN</sub> ) <sup>513</sup> / <sup>1024</sup> |
| 1000                 | 0000      | 00(00) | $_{2}(v_{\text{REFIN}})^{512}$ $_{1024} = v_{\text{REFIN}}$  |
| 0111                 | 1111      | 11(00) | 2(v <sub>REFIN</sub> ) <sup>511</sup> /1024                  |
| 0000                 | :<br>0000 | 01(00) | :<br>2(V <sub>REFIN</sub> ) <sup>1</sup> /1024               |
| 0000                 | 0000      | 00(00) | 0 V  |

(1) A 10-bit data word with two bits below the LSB bit (sub-LSB) with 0 values must be written since the DAC input latch is 12 bits wide.



## **13. ORDERING INFORMATION**

| Part<br>Number | Device<br>Marking | Package<br>Type | Body size<br>(mm) | Temperature<br>(°C) | MSL  | Transport<br>Media | Package<br>Quantity |
|----------------|-------------------|-----------------|-------------------|---------------------|------|--------------------|---------------------|
| XL5615         | XL5615            | SOP8            | 4.90 * 3.90       | - 40 to 85          | MSL3 | T&R                | 2500                |
| XD5615         | XD5615            | DIP8            | 9.25 * 6.38       | - 40 to 85          | MSL3 | Tube 50            | 2000                |

### **Ordering Information**

## 14. DIMENSIONAL DRAWINGS





